

FORM PTO-1449/A and B (Modified) INFORMATION DISCLOSURE STATEMENT BY APPLICANT		APPLICATION NO.: Unassigned		ATTY. DOCKET NO.: ^{10/727682} S1022.81108US00	
		FILING DATE: Herewith		CONFIRMATION NO.: Unassigned	
		APPLICANT: Hilal EZZEDDINE et al.			
		GROUP ART UNIT: Unassigned		EXAMINER: Unassigned	
Sheet	1	of	1		

U.S. PATENT DOCUMENTS

Examiner's Initials	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYYY
		Number	Kind Code		
DT	*	4,937,541		Allen F. Podell et al.	06/26/90
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FOREIGN PATENT DOCUMENTS

Examiner's Initials	Cite No.	Foreign Patent Document			Name of Patentee or Applicant of Cited Document (not necessary)	Date of Publication of Cited Document MM-DD-YYYY	Translation (Y/N)
		Office/Country	Number	Kind Code			

OTHER ART — NON PATENT LITERATURE DOCUMENTS

Examiner's Initials	Cite No	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)
		French Search Report from French Patent Application 02/15477, filed December 6, 2002	
DT		Ojha S. et al. "Reduced Size RF Coupler Design For Specialized Load Requirements" Circuits and Systems, 1997. Proceedings Of The 40 th Midwest Symposium on Sacramento, CA, USA 3-6 Aug. 1997, New York, NY USA, IEEE, US, August 3, 1997, pages 595-598	
DT		Patent Abstracts of Japan, vol. 005, no. 125 (E-069), August 12, 1981 & JP 56 062402 A (Fujitsu Ltd.) May 28, 1981	
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DT		Cne J-L et al. "A High-Directivity Microstrip Directional Coupler With Feedback Compensation" 2002 IEEE MTT-S International Microwave Symposium Digest. (IMS 2002). Seattle, WA June 2-7, 2002, IEEE MTT-S International Microwave Symposium, New York, NY: IEEE, US, vol. 1 of 3, June 2, 2002, pages 101-104	
DT		Patent Abstracts of Japan, vol. 2003, no. 02, February 5, 2003 & JP 2002 299922 A (Kyocera Corp.), October 11, 2002	

EXAMINER <i>Dean Tokuda</i>	DATE CONSIDERED <i>2/23/05</i>
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